

Notice of References Cited	Application/Control No. 09/924,926	Applicant(s)/Patent Under Reexamination SAID, AMIR	
	Examiner Fred Ferris	Art Unit 2128	Page 1 of 1

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*	A	US-5,835,625 A	11-1998	Fitzpatrick et al.	382/165
*	B	US-5,891,394 A	04-1999	Drocourt et al.	422/50
*	C	US-2003/0016877 A1	01-2003	Baharav et al.	382/248
*	D	US-6,449,384 B2	09-2002	Laumeyer et al.	382/104
*	E	US-6,011,595 A	01-2000	Henderson et al.	348/590
*	F	US-6,430,312 B1	08-2002	Huang et al.	382/165
*	G	US-6,832,006 B2	12-2004	Savakis et al.	382/239
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Statistical Pattern Recognition", A. Webb, Chapter 1, pp. 1-31, Oxford University Press, 1999 teaches statistical analysis in pattern recognition.
	V	"Robust Mesh Watermarking", Praun et al, ACM 1999
	W	"Statistical cues for Domain Specific Image Segmentation with Performance Analysis", Konishi et al, IEEE 1063-6919/00, 2000 IEEE
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.